

Notice of References Cited	Application/Control No. 10/023,438	Applicant(s)/Patent Under Reexamination EIDEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0069004	04-2003	Hamynen et al.	455/412
	B	US-2002/0078157	06-2002	Matsumoto, Shigeki	709/206
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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